

Search Notes



Application/Control No.

10/687,705

Examiner

Sara W. Crane

Applicant(s)/Patent under Reexamination

IWASE ET AL.

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
257	48 618	5/05	SWC
	620		
257	48	9/05	SWC
	618		
	620		
	622		
	797		
148	33.2		
438	16		
	401		
	462		
428	66.7		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPub search 9/05 SWC			
attached			
and as above			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST		
semiconductor and wafer and bevel and (ID or mark)	5/05	SWC
wafer and (bevel with edge) and semiconductor		
update see printout	9/05	SWC